

The Bypass Capacitor in High-Speed Environments



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Introduction

High-speed switching environments generate noise on power lines (or planes) due to the charging and discharging of internal and external capacitors of an integrated circuit. The instantaneous current generated with the rising and falling edges of the outputs causes the power line (or plane) to ring. This behavior can violate the V_{CC} recommended operating conditions or generate false signals, creating serious problems. A simple and easy solution must be considered to prevent such a problem from occurring. This solution is the bypass capacitor.

Bypass Definition

A bypass capacitor stores an electrical charge that is released to the power line whenever a transient voltage spike occurs. It provides a low impedance supply, thereby minimizing the noise generated by the switching outputs of the device.

Bypassing Considerations

A system without bypassing techniques can create severe power disturbance and cause circuit failures. Figure 1 shows the V_{CC} line of the 'ABT541 ringing while all outputs are switching. Note that there is no bypass capacitor at the V_{CC} pin. There are a few issues that should be considered when bypassing power lines (or planes).

- The capacitor type
- The capacitor placement
- The output load effect
- The capacitor size

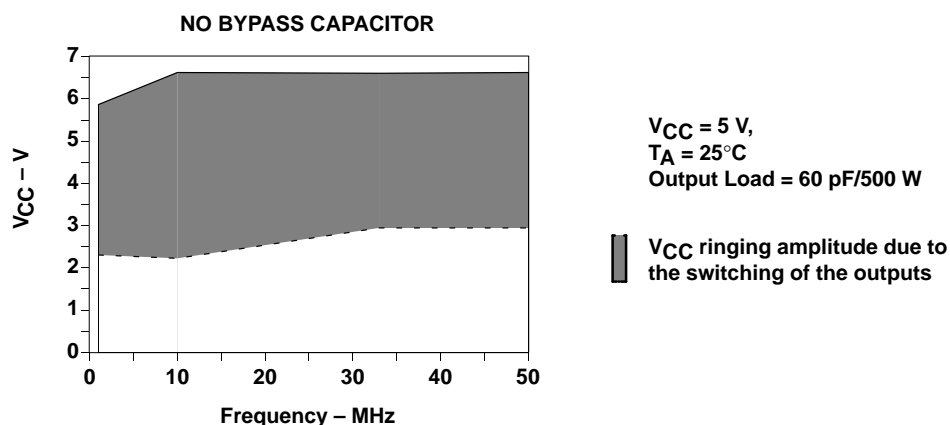


Figure 1. V_{CC} Line Disturbance vs Frequency

Capacitor Type

In a high-speed environment the lead inductances of a bypass capacitor become very critical. High-speed switching of a part's outputs generates high frequency noise ($> 100\text{ MHz}$) on the power line (or plane). These harmonics cause the capacitor with high lead inductance to act as an open circuit, preventing it from supplying the power line (or plane) with the current needed to maintain a stable level, and resulting in functional failure of the circuit. Therefore, bypassing a power line (or plane) from the device internal noise requires capacitors with very small inductances. That is why the multilayer ceramic chip capacitors (MLC) are more favorable than others for bypassing power lines (or planes). They exhibit negligible internal inductance, thereby allowing the charge to flow easily, when needed, without degradation.

Capacitor Placement

Most of the printed circuit boards are designed to maintain a short distance between power and ground. This is done by laminating the power line (or plane) with the ground plane and can be electrically approximated with lumped capacitances as shown in Figure 2. However, this is not enough to have a reliable system, and another technique must be considered to provide a low-impedance path for the transient current to be grounded. This can be done by placing the bypass capacitor close to the power pin of the device.

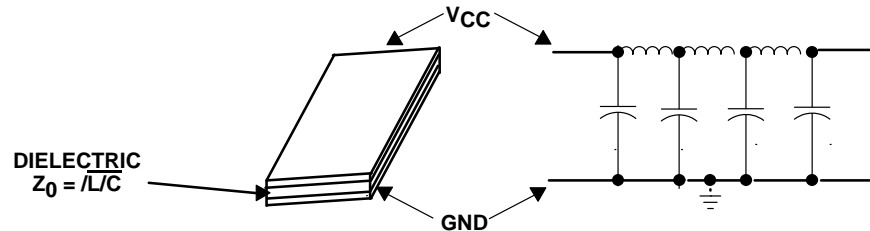


Figure 2. Typical Power Layout

Why This Location Is Very Important

Consider a device driving a line from low to high having an impedance ($Z \cong 100 \Omega$) and a supply voltage ($V_{CC} = 5 \text{ V}$) (see Figure 3). In order for the device to change state, an output current ($I = 50 \text{ mA}$) is needed instantaneously. Note that for eight outputs switching $I = 50 \times 8 = 400 \text{ mA}$. This current is provided by the power line (or plane) in a period \leq the rise time of the output (approximately 3 ns for ABT). The bypass capacitor must supply the charge in that same period of time to avoid V_{CC} drop, therefore distance becomes an important issue. Line inductances can block the charge from flowing, leaving the power line (or plane) disturbed.

Using the formula for paralleled wires:

$$L = l \frac{\mu_0}{\pi} \ln \frac{d}{r} \quad (1)$$

where d is the distance between the wires, r is the radius of the wires, l is the length of the wires and μ_0 is the permeability of medium between wires, one can note that the inductance (L) is directly proportional to the distance between the lines as well as the length of the lines. Therefore, by reducing the loop ABCD in Figure 3, we can minimize the inductance and allow the capacitor to do its function more efficiently, and hence keep the noise off the power line (or plane).

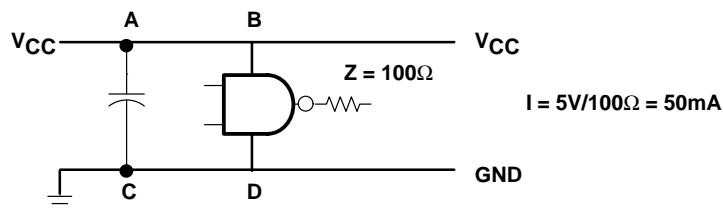


Figure 3. Capacitive Storage (Bypass Capacitor)

Several tests were done on an 'ABT541 device to study the behavior of its power line (or plane) as the outputs switch simultaneously. This data is taken at different distances from the power pin (0.3, 1, and 2 inches) using four chip capacitors (0.001, 0.01, 0.1, and 1 μF), with an input frequency of 33 MHz and all eight outputs switching (worst case). Figure 4 shows the line disturbance increases as the capacitor is moved away from the power pin.

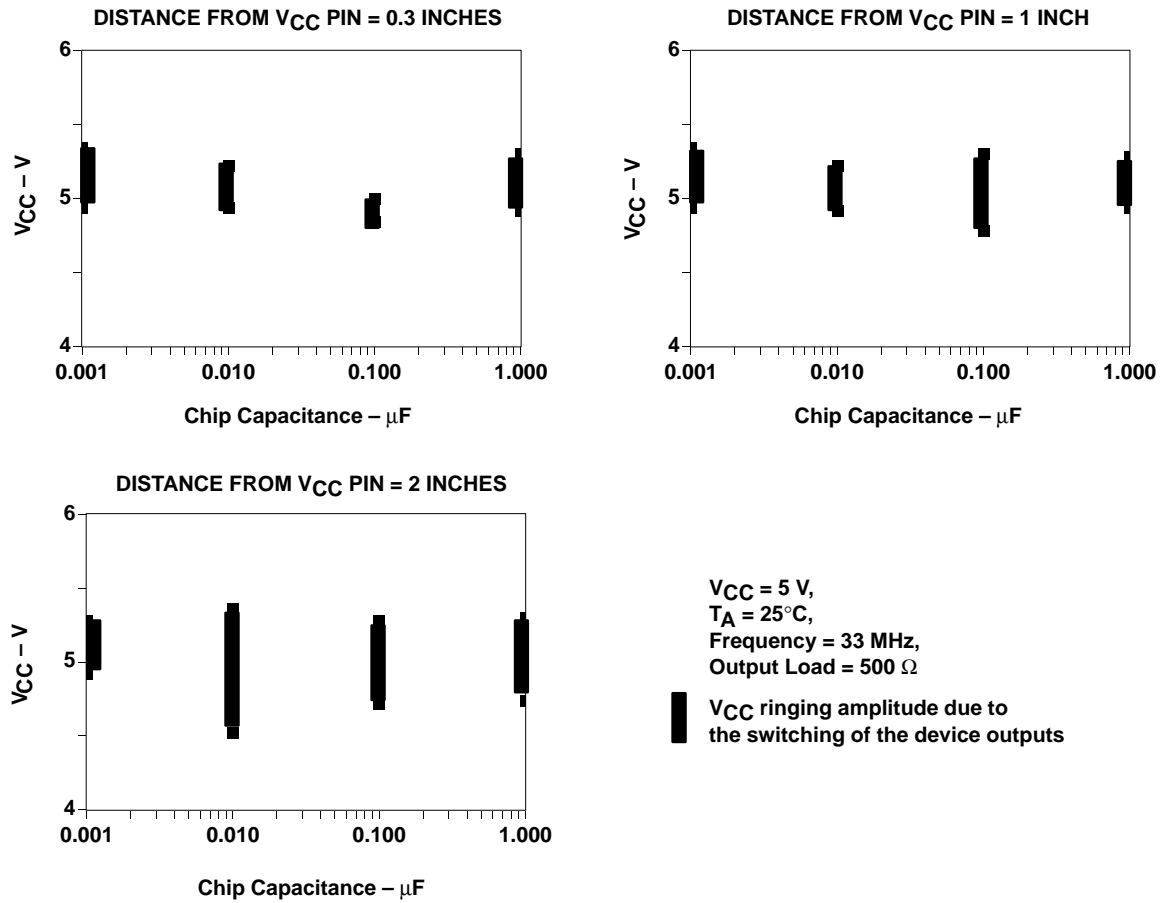


Figure 4. V_{CC} Line Disturbance vs Cap Size at Different Distances

Output Load Effect

Capacitive loads combined with increased frequency result in higher transient current and possible V_{CC} oscillation. If the output load is purely resistive, the increase in frequency does not affect the rising and falling edge of the outputs, therefore not increasing the V_{CC} line disturbance. Figure 5 shows the power line behavior across frequency while driving a resistive load only, and Figure 6 shows the same plot with an additional 60-pF capacitive load.

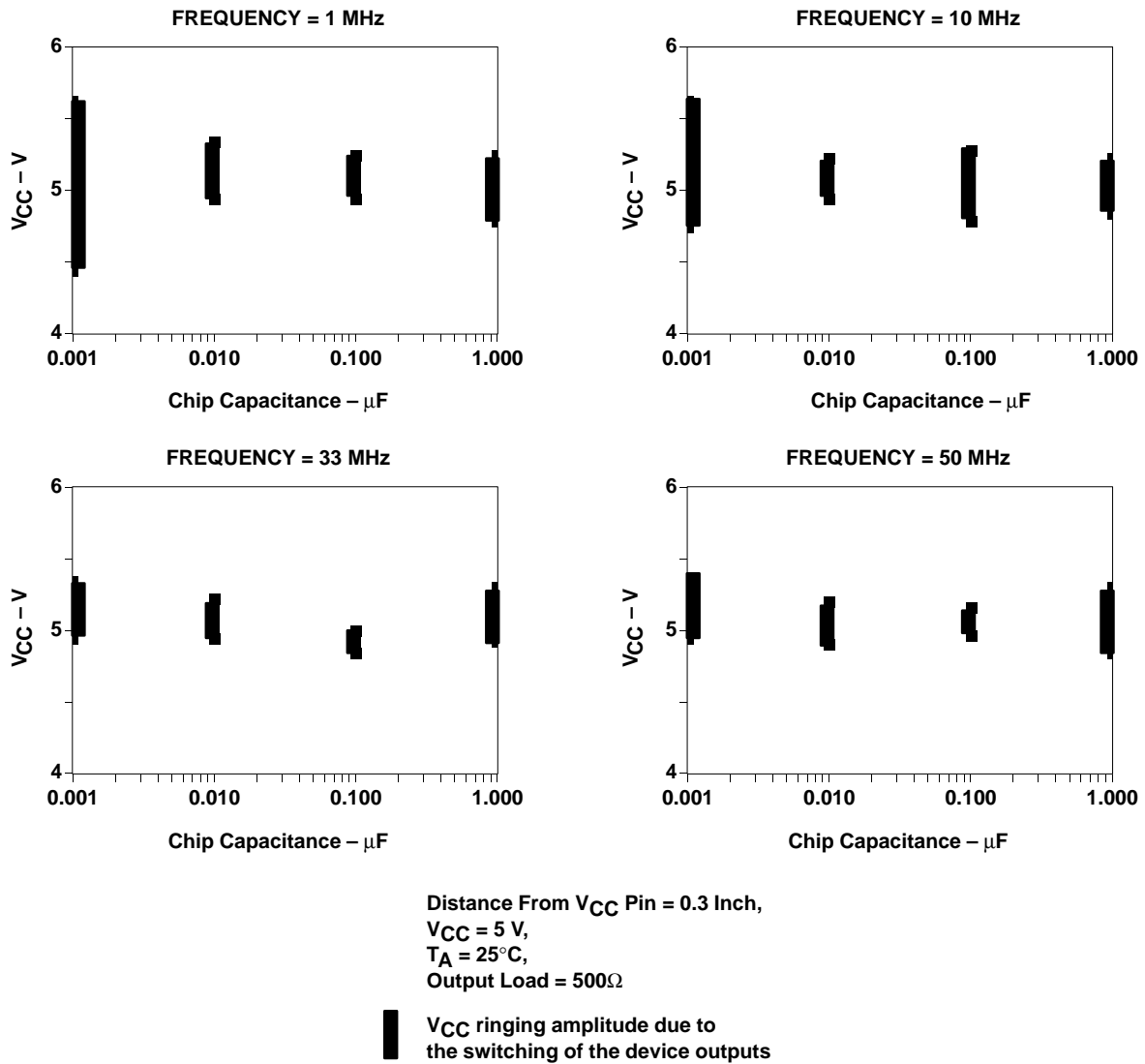


Figure 5. V_{CC} Line Disturbance vs Cap Size With Resistive Load at Different Frequencies

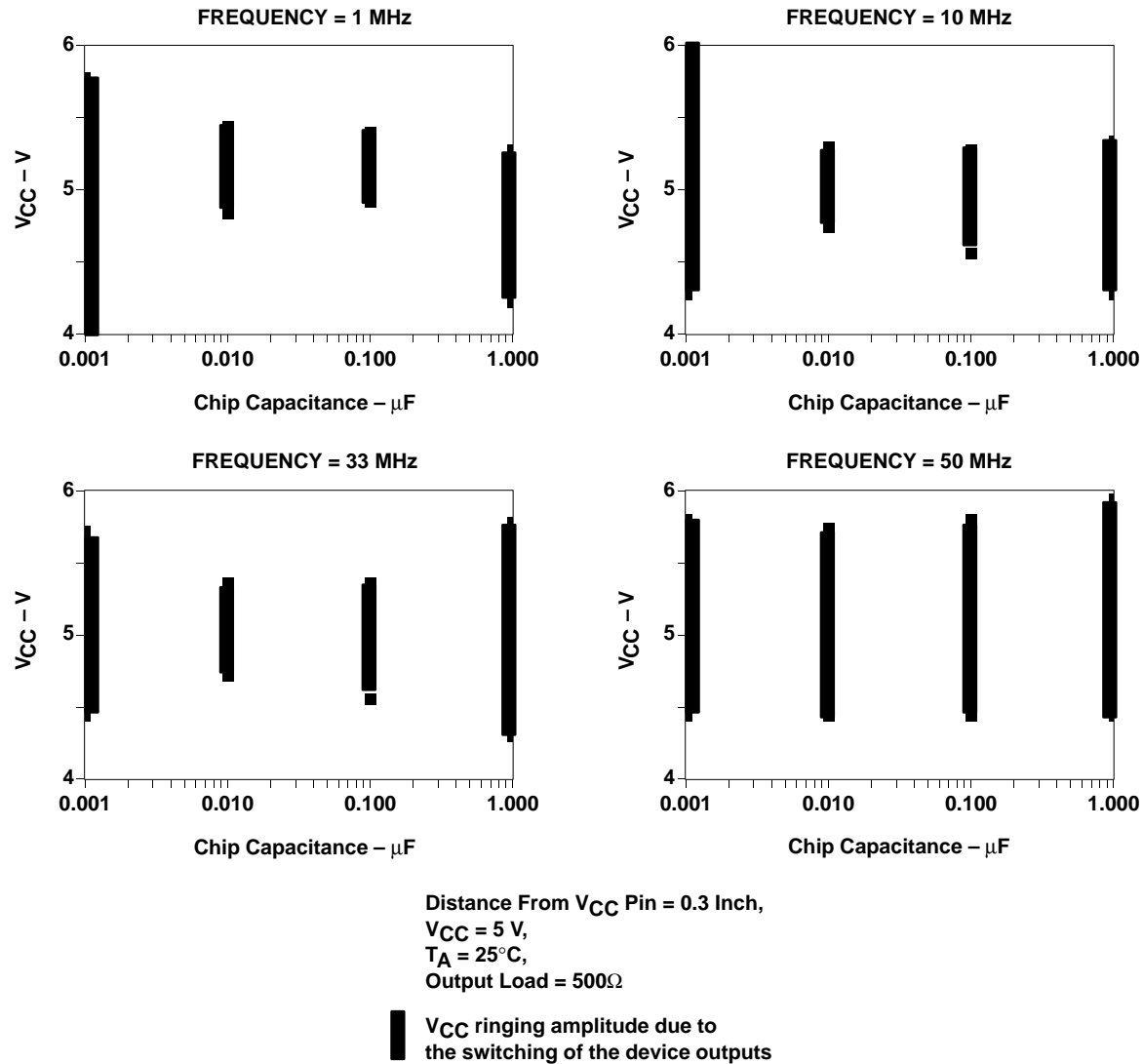


Figure 6. V_{CC} Line Disturbance vs Cap Size With 60-pF Load at Different Frequencies

When driving large capacitive loads, more charge will need to be supplied to the output load, resulting in a slower rising or falling edge. However, if the bypass capacitor is not capable of providing the needed charge, power lines (or planes) start to ring and eventually oscillate causing failures across the board. These oscillations can be of a great amplitude, 2 to 3 V p-to-p. Figure 7 shows these oscillations at four different loads (0, 60, 115 and 200 pF) using four different bypass capacitors (0.001, 0.01, 0.1, and 1 μF).

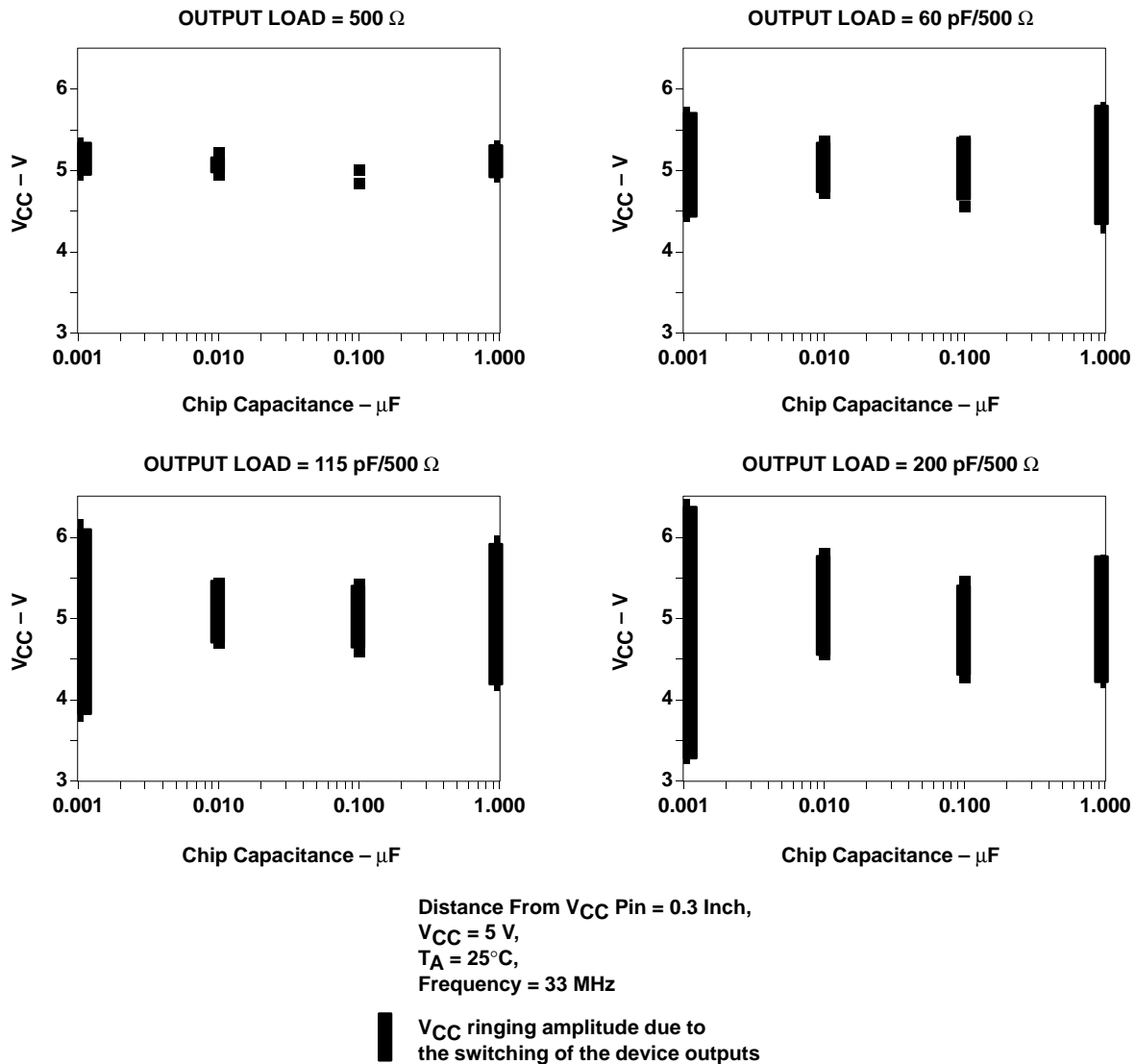


Figure 7. V_{CC} Line Disturbance vs Cap Size at Different Capacitive Loads

Capacitor Size

How can we choose the right bypass capacitor? The most important parameter is the capability of supplying instantaneous current when it is needed.

There are two ways for calculating the bypass capacitor size for a device:

1. One must know the amount of current needed to switch one output from low to high (I), the number of outputs switching (N), the time required for the capacitor to charge the line (ΔT), and the drop in V_{CC} that can be tolerated (ΔV).

The following equation can be used:

$$C = \frac{I \times N \times \Delta T}{\Delta V} \quad (2)$$

where ΔT and ΔV can be assumed.

For example, say one has the following parameters: $\Delta V = 0.1$ V, $\Delta T = 3$ ns, $N = 8$, and I can be obtained from either Figure 3, for rough estimate or from the plot in Figure 8, assuming 50-MHz frequency. We are going to use the latter parameter for our example, $I = 44$ mA.

Then the equation is as follows:

$$C = \frac{44 \times 10^{-3} \times 8 \times 3 \times 10^{-9}}{0.1} = 10080 \times 10^{-12} = 0.01 \mu\text{F} \quad (3)$$

2. Several of the capacitor manufacturers specify the maximum pulse slew rate. This allows the capacitor's maximum current to be calculated. For example, a 0.1- μF capacitor rated at 50 V/ μs can supply: $i = cdv/dt = 0.1 \times 50 = 5$ A. This current is greater than the maximum current ($I \times N = 44 \text{ mA} \times 8$ outputs switching = 352 mA) required by the device used in the previous example.

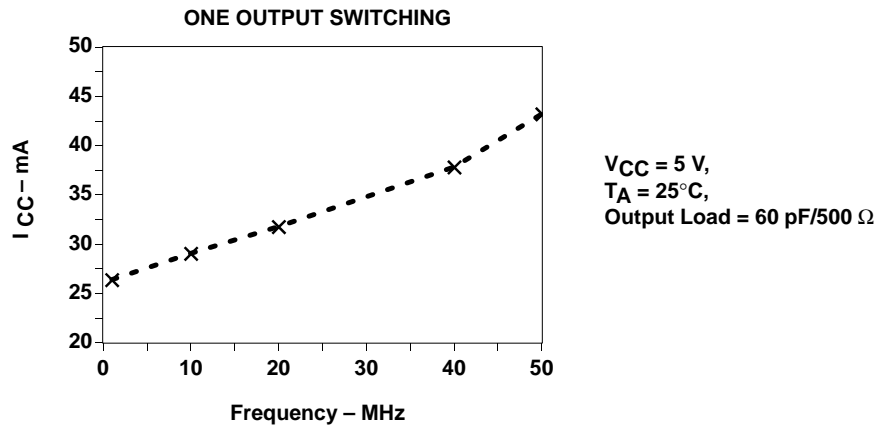


Figure 8. I_{CC} vs Frequency

Summary

From what was mentioned previously, one can see how important is the bypassing technique. Bypass capacitors play a major role in achieving reliable systems. The absence of the bypass capacitor can generate false signals and create major problems across the entire board. Figure 1 shows the undesired ringing caused by simultaneously switching the outputs of the 'ABT541. Also, choosing a capacitor with negligible lead inductance can avoid unpredictable behavior at high frequencies. Locating the capacitor closer to the V_{CC} pin of a device can avoid further complications and eliminate the ringing entirely. Figure 6 shows the V_{CC} line behavior with the bypass capacitor placed 0.3 inches away from the V_{CC} pin, whereas Figure 9 shows the same plot with the same load, but the bypass capacitor is located at the pin, one can see the dramatic improvement achieved in the latter case. This technique can also be applied to Texas Instruments *Widebus*™ family by bypassing all V_{CC} pins. This was proven to be the most effective method for eliminating the V_{CC} line ringing. It is always important to minimize the loop between the V_{CC} pin, the ground, and the bypass capacitor. Finally, choosing the capacitor size by using either method mentioned earlier is highly recommended. If one considers all these issues, a good bypass technique can be achieved.

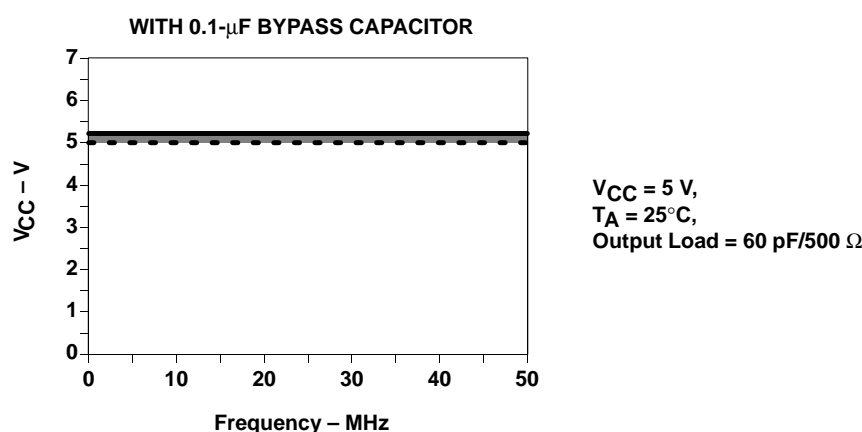


Figure 9. V_{CC} Line Disturbance vs Frequency

References

- [1] Texas Instruments, *Advanced Schottky Family (ALS/AS) Applications*
- [2] Walton, D., *P.C.B. Layout for High-Speed Schottky TTL*